# **Special Issue**

# Radiation Tolerant Electronics, Volume III

## Message from the Guest Editors

Research on radiation-tolerant electronics has increased rapidly over the last few years, resulting in many interesting approaches to model radiation effects and design radiation-hardened integrated circuits and embedded systems. The main aim of this Special Issue is to seek high-quality submissions that highlight emerging applications, address recent breakthroughs in modeling radiation effects in advanced electronic devices and circuits, the design of radiation-hardened analog, mixed-signal, RF and digital integrated circuits and radiation hardness testing methodologies. The topics of interest include, but are not limited to:

- Basic mechanisms of radiation effects in electronic devices
- Compact modeling of radiation effects and circuit/layout level optimization (TID and SEE)
- Radiation effects in power devices/circuits
- Design of radiation-hardened integrated circuits (analog/RF/mixed-signal/digital)
- Radiation hardening and fault tolerance in FPGAs
- Radiation hardness assurance testing

### **Guest Editors**

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## Deadline for manuscript submissions

closed (29 February 2024)



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## Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

### Editor-in-Chief

Prof. Dr. Flavio Canavero

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